## nexperia

## **Quarterly Reliability Monitoring Results**

Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier		User Part Number						
Nexperia B.V.		BC847AW						
Name of Laboratory Assembly reliability labs Test		Part Description						
		Nexperia DHAM Small Signal Bipolar Transistor						
		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# 1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
# 2	<b>PC</b> Preconditioning	JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles	1265	c0000	<u>.</u>		
# 2	Precondicioning	-	3 Cycles	1265	69890	0		
# 5	<b>HTRB</b> High Temperature Reverse Bias	$\label{eq:milling} \begin{array}{l} \text{MIL-STD-750-1} \\ \text{M1039 Method A} \\ \text{Tj} = \text{Tjmax}, \mbox{ Vr} = 100\% \mbox{ of max. datasheet} \\ \text{reverse voltage} \end{array}$	1000 hours	316	18920	0		
# 7	<b>TC</b> Temperature Cycling	JESD22-A104 -65 °C to Tjmax, not to exceed 150°C	200 cycles	260	15680	0		
# 8 <b>or</b>	<b>UHAST</b> Unbiased HAST	JESD22-A118 Tamb = 130 °C, RH = 85 %	— 96 hours	270	16360	0		
# 8a	<b>AC</b> Autoclave	JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)						
# 9	<b>H3TRB</b> High Humidity High Temperature Reverse Bias	JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage <sup>[1]</sup>	1000 hours	262	15760	0		
# 10	<b>IOL</b> Intermittent Operating Life	MIL-STD-750 Method 1037 ton = toff, devices powered to insure $\Delta Tj$ = 100 °C for 15000 cycles	333 hours	262	15760	0		
# 20	<b>RSH</b> Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C	10 s	211	6330	0		
# 21	<b>SD</b> Solderability	J-STD-002	1151/	468	4680	0		

[1]The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia DHAM	Small Signal Bipolar Transistor	18920	0	0,22	4,46E+09

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